

EAST Search History

10/6/4,997

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S44	0	(processor AND mixed signal semiconductor device tester unit AND wafer testing AND package testing AND mixed signal semiconductor device AND interpreted software language AND interactive test pascal AND software computation module AND compiled software language AND test script AND first test AND second test). clm.	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/04/11 15:05